L Number	Hits	Search Text	DB	Time stamp
1	2961	(705/1).CCLS.	USPAT;	2004/07/29
_		(0.00.0)	US-PGPUB;	13:48
			EPO; JPO;	13333
			DERWENT	
3	1666	wafer adj testing	USPAT;	2004/07/29
		waret au teeting	US-PGPUB;	
			EPO; JPO;	10.10
			DERWENT	
4	o	((705/1).CCLS.) and (wafer adj test\$)	USPAT;	2004/07/29
-		((100/1/100201) and (trains au) (00(4))	US-PGPUB;	13:48
			EPO; JPO;	10.40
			DERWENT	
5	6442	probe adj card	USPAT;	2004/07/29
3	0442	probe auj caru	US-PGPUB;	13:49
			EPO; JPO;	
	1		DERWENT	
6	0	((705/1).CCLS.) and (probe adj card)	USPAT;	2004/07/29
•	•	((705/1).coes.) and (probe adjicard)	US-PGPUB;	
			EPO; JPO;	15.45
			DERWENT	
7	15	automat\$ adj wafer adj testing	USPAT;	2004/07/29
*	15	automats auj waier auj testing	US-PGPUB;	13:52
			EPO; JPO;	13:32
			DERWENT	
	0	automat\$ adj wafer adj testing and network	USPAT;	2004/07/29
8		automats auj water auj testing and network	US-PGPUB;	13:51
			EPO; JPO;	13.31
			DERWENT	
9	76	automat\$ and (wafer or probe) adj4 testing	USPAT;	2004/07/29
9	1	and server	US-PGPUB;	13:54
		and server	EPO; JPO;	13.34
			DERWENT	
10	10	(automat\$ and (wafer or probe) adj4 testing	USPAT;	2004/07/29
10	'8	and server) and @pd<20010917	US-PGPUB;	14:14
		ana server, ana epa-20010311	EPO; JPO;	••••
			DERWENT	
11	2	("20020069114").PN.	USPAT;	2004/07/29
''	-	1 LUULUUU I I 7,FIA.	US-PGPUB;	14:03
			EPO; JPO;	14.03
			DERWENT	
12	2	("6223092").PN.	USPAT;	2004/07/29
12	_	CZZSOSZ J.FIG.	US-PGPUB;	14:09
			EPO; JPO;	17.03
			DERWENT	
13	6621	design\$ adj2 probe	USPAT;	2004/07/29
13	6621	uesigna aujz probe	US-PGPUB;	14:14
			EPO; JPO;	17017
	L		DERWENT	

14	2	((705/1).CCLS.) and (design\$ adj2 probe)	USPAT;	2004/07/29
			US-PGPUB;	14:10
			EPO; JPO;	
			DERWENT	
15	149	design\$ adj2 probe adj2 card	USPAT;	2004/07/29
			US-PGPUB;	14:14
			EPO; JPO;	
			DERWENT	
16	69	(design\$ adj2 probe adj2 card) and	USPAT;	2004/07/29
		@pd<20010917	US-PGPUB;	14:26
			EPO; JPO;	
			DERWENT	
17	28732	wafer and testing	USPAT;	2004/07/29
			US-PGPUB;	14:15
			EPO; JPO;	
			DERWENT	
18	56	((design\$ adj2 probe adj2 card) and	USPAT;	2004/07/29
		@pd<20010917) and (wafer and testing)	US-PGPUB;	14:16
			EPO; JPO;	
			DERWENT	
19	166190	server and network	USPAT;	2004/07/29
			US-PGPUB;	14:16
			EPO; JPO;	
	_		DERWENT	
20	2	(((design\$ adj2 probe adj2 card) and	USPAT;	2004/07/29
		@pd<20010917) and (wafer and testing))	US-PGPUB;	14:24
		and (server and network)	EPO; JPO;	
			DERWENT	
21	14	automatic adj design adj2 integrated adj	USPAT;	2004/07/29
		circuit	US-PGPUB;	14:25
			EPO; JPO;	
22	0	(server and network) and (automatic adj	DERWENT	2004/07/29
22		design adj2 integrated adj circuit)	USPAT; US-PGPUB;	14:25
		design adjz integrated adj circuity	EPO; JPO;	14:25
			DERWENT	
23	0	((705/1).CCLS.) and (automatic adj design	USPAT;	2004/07/29
		adj2 integrated adj circuit)	US-PGPUB;	14:25
		anja iniogratoa aaj onoanj	EPO; JPO;	17127
1			DERWENT	
24	22	automatic\$ adj design adj2 (integrated adj	USPAT;	2004/07/29
		circuit or chip)	US-PGPUB;	14:26
			EPO; JPO;	· ··
			DERWENT	
25	o	(server and network) and (automatic\$ adj	USPAT;	2004/07/29
		design adj2 (integrated adj circuit or chip))	US-PGPUB;	14:26
			EPO; JPO;	
			DERWENT	
26	0	((705/1).CCLS.) and (automatic\$ adj design	USPAT;	2004/07/29
		adj2 (integrated adj circuit or chip))	US-PGPUB;	14:26
	.		EPO; JPO;	
			DERWENT	

27	15	((automatic adj design adj2 integrated adj	USPAT;	2004/07/29
		circuit) or (automatic\$ adj design adj2 (US-PGPUB;	14:32
		integrated adj circuit or chip))) and	EPO; JPO;	
		@pd<20010917	DERWENT	
28	12	5824570.URPN.	USPAT	2004/07/29
				14:27
29	337441	computer and automatic\$	USPAT;	2004/07/29
			US-PGPUB;	14:30
			EPO; JPO;	
			DERWENT	
30	1378	(computer and automatic\$) and ((wafer adj	USPAT;	2004/07/29
		test\$) or (design\$ adj2 probe) or (design\$	US-PGPUB;	14:31
		adj2 probe adj2 card))	EPO; JPO;	
			DERWENT	
31	7227	((705/1).CCLS.) andn ((computer and	USPAT;	2004/07/29
		automatic\$) and ((wafer adj test\$) or	US-PGPUB;	14:31
		(design\$ adj2 probe) or (design\$ adj2 probe	EPO; JPO;	
		adj2 card)))	DERWENT	
32	2	((705/1).CCLS.) and ((computer and	USPAT;	2004/07/29
52	_	automatic\$) and ((wafer adj test\$) or	US-PGPUB;	14:32
		(design\$ adj2 probe) or (design\$ adj2 probe	EPO; JPO;	14.02
		adj2 card)))	DERWENT	
33	100	(server and network) and ((computer and	USPAT;	2004/07/29
33	100	automatic\$) and ((wafer adj test\$) or	1 *	14:32
		(design\$ adj2 probe) or (design\$ adj2 probe	US-PGPUB;	14:32
			EPO; JPO; DERWENT	
24		adj2 card)))		0004/07/00
34	11	((server and network) and ((computer and	USPAT;	2004/07/29
		automatic\$) and ((wafer adj test\$) or	US-PGPUB;	14:38
		(design\$ adj2 probe) or (design\$ adj2 probe	EPO; JPO;	
25	4540	adj2 card)))) and @pd<20010917	DERWENT	
35	1548	(700/96,97,117).CCLS.	USPAT;	2004/07/29
			US-PGPUB;	14:39
			EPO; JPO;	
20	45.40	(700/000) 0010	DERWENT	0004/07/00
36	4542	(709/203).CCLS.	USPAT;	2004/07/29
			US-PGPUB;	14:39
			EPO; JPO;	
		(UOO - LOOUN BA)	DERWENT	0004/07/07
37	0	("03and36").PN.	USPAT;	2004/07/29
			US-PGPUB;	14:39
			EPO; JPO;	
		///	DERWENT	
38	0	("03and35").PN.	USPAT;	2004/07/29
			US-PGPUB;	14:39
			EPO; JPO;	
			DERWENT	
39	3	(wafer adj testing) and	USPAT;	2004/07/29
		(((700/96,97,117).CCLS.) or	US-PGPUB;	14:41
		((709/203).CCLS.))	EPO; JPO;	
			DERWENT	

40	1	(design\$ adj2 probe adj2 card) and	USPAT;	2004/07/29
		(((700/96,97,117).CCLS.) or	US-PGPUB;	14:41
		((709/203).CCLS.))	EPO; JPO;	
			DERWENT	
41	2	(automat\$ and (wafer or probe) adj4 testing	USPAT;	2004/07/29
İ		and server) and (((700/96,97,117).CCLS.) or	US-PGPUB;	14:42
		((709/203).CCLS.))	EPO; JPO;	
			DERWENT	
-	2	("6714828").PN.	USPAT;	2004/07/29
			US-PGPUB;	13:48
			EPO; JPO;	
			DERWENT	